

Determination of the Distribution of Sulphur in Wheat Starchy Endosperm Cells Using Secondary Ion Mass Spectroscopy (SIMS) Combined with Isotope Enhancement

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ABSTRACT

Secondary ion mass spectrometry (SIMS) is a sensitive, high resolution technique capable of determining the location of elements or ions in a sample down to sub-cellular levels. The distribution of elements or ions are superimposed onto an image of the plant cell or tissue generated by ion-induced secondary electrons, allowing a visual representation of their positions in the sample. The elements are separated by their mass/charge ratios which can lead to a loss of sensitivity when separating signals from elements with very similar masses such as ${}^{16}O_2$ (31·990 a.m.u.) and ${}^{32}S$ (31·972 a.m.u.). The abundance of ${}^{34}S$ isotope was, therefore enriched, allowing sulphur to be located at the starch granule/protein interface of the mature wheat grain. This demonstrates that isotopic enrichment can be used to extend the applications of SIMS technology to biological systems.

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INTRODUCTION

The identification of the location of individual components at the sub-cellular level is one of the major challenges facing plant cell biologists. Proteins can often be located in fixed (i.e., dead) material using specific antibodies for microscopy or in living tissues using laser confocal microscopy using specific fluorescence labels. However, the localisation of inorganic components is more problematic with all currently available methods (e.g., energy dispersive X-ray analysis $(EDX)^1$ X-ray photoelectron spectroscopy $(XPS)^2$ and electron energy loss spectroscopy $(EELS)^3$ having significant limitations in terms of sensitivity, resolution and range of detectable elements and isotopes.

Secondary ion mass spectroscopy (SIMS) is a highly sensitive technique capable of mapping elements on a surface of a sample with sub-micron resolution and parts per million sensitivity⁴. It is based on the bombardment of samples with a primary ion beam to liberate secondary particles, some of which are ionised and can be captured and analysed to determine their mass to charge ratio. A wide range of elements and isotopes can be detected and identified provided that they differ in mass.

ABBREVIATIONS USED: HMW = high molecular weight; LMW = low molecular weight; SEM = secondary electron microscopy; SIMS = secondary ion mass spectroscopy; ${}^{34}S$ = sulphur isotope mass 34 a.m.u.; ${}^{32}S$ = sulphur isotope mass 32 a m u : ${}^{16}O$ = oxygen isotope mass 16 a m u

mass 32 a.m.u.; ¹⁶O = oxygen isotope mass 16 a.m.u. **Corresponding Author. Fax:* +44-1275-394-299; *E-mail: peter.shewry@bbsrc.ac.uk*

We have recently used an improved SIMS technique to map the distribution of minerals (K⁺, Na⁺, Ca²⁺, Mg²⁺ and PO₂⁻), proteins (identified by CN⁻ signals) and carbohydrates (identified by C₂ and O⁻ signals) in aleurone and starchy endosperm cells of mature wheat grain, with excellent resolution and sensitivity⁵. However, we were unable to map the distribution of sulphur reliably. The major isotope (³²S) has a mass of 31.972 which, is close to that of ¹⁶O₂ (31.990) and although the present instrument is capable of resolving these species (whose mass difference of 0018 is higher than the maximum resolution limit of mass differences of 0.016) this is accompanied by an unacceptable loss of sensitivity.

Furthermore, although the naturally occurring isotopic form of sulphur ³⁴S is distinguishable from ¹⁶O₂ by the SIMS technique, it is only present at about 4.3% of all the sulphur atoms in the environment⁶ and hence in the wheat grain⁷.

The distribution of sulphur is of particular interest to cereal chemists as sulphur-rich seed proteins contribute to important functional properties for milling (grain texture) and baking (visco-elasticity) and it has been shown that increasing sulphur concentration in wheat grain results in increased dough extensibility⁸. We have therefore enriched the abundance of ³⁴S in developing grain of wheat and determined its distribution in mature starchy endosperm cells by SIMS.

MATERIALS AND METHODS

Plant growth

An S-deficient soil was collected from Woburn, Bedfordshire, air-dried and sieved to $<5 \,\mathrm{mm}$. The soil is a sandy loam, containing 1.0% organic C and 2.0 mg kg^{-1} of extractable sulphate-S. Soil pH was 6.5. Two kg air-dried soil was weighed and placed in a 15 cm plastic pot. Each pot received a basal nutrient dressing of 400 mg N (NH₄NO₃), 100 mg P (KH_2PO_4) , $12\bar{6}$ mg K (KH_2PO_4) , 75 mg Mg $(MgCl_2 \cdot 6H_2O)$, 5 mg Mn $(MnCl \cdot 4H_2O)$, 1 mg Cu $(CuCl_2 \cdot 2H_2O)$, 2 mg Zn $(ZnCl_2)$, 1 mg B (H_3BO_3) and 0.5 mg Mo (Na₂MoO₄). The nutrients were dissolved in water and mixed thoroughly into the soils. Soils were then adjusted to 70% water holding capacity using deionised water. Seeds of the transgenic wheat (line B73-6-1) and its parent line (L88-6) were germinated on moistened filter paper in the dark and then planted into the pots (2 seedlings per pot). At the tillering stage, 20 mg of S (K₂SO₄) labelled with 30 atom % of the stable isotope ³⁴S was added in solution to each pot, together with 100 mg N (KNO₃) containing 99.9 atom % ¹⁵N. The ³⁴S labelled K₂SO₄ was produced from elemental S (90 atom % of ³⁴S; Sigma Chemical Company, St Louis, USA)⁷ Plants were grown in a glasshouse under controlled environment conditions: day/night durations of 14/10 h and day/night temperatures of 20 °C/16 °C. The natural light was supplemented with 1 kW SON-T lamps to maintain a minimum photon flux of 250 µmol m⁻² s⁻¹. The pots were watered with deionised water and the grains harvested at maturity (110 days after planting).

Sample preparation

Transverse sections of dry mature wheat grains were cut using a razor blade and fixed using a solution of 3.7% paraformaldehyde/2.5% glutaraldehyde in 25 mM PIPES buffer pH 6.9^9 . The samples were vacuum infiltrated with the fixation solution for 30 min followed by 4 h incubation with continuous rotation at atmospheric pressure and then washed in 25 mM PIPES buffer for $3 \times 15 \text{ min}$ periods. The fixed samples were dehydrated in an increasing ethanol:water series (30, 50, 70, 80, 90, 100 and 100% ethanol), incubating for 30 min in each solution with continuous rotation.

A Polyscience Inc JB-4TM embedding kit was used to embed the samples in resin. The samples were incubated with the catalysed infiltration resin for 2×30 min, $1 \times$ overnight and 1×30 min after which the samples were placed in the embedding solution (as per manufacturer's protocols) in aerobically sealed containers for 60 min. The embedded samples were removed from their containers and a glass knife mounted on an ultramicrotome (Ultracut Reichert-Jung) provided a flat surface for analysis.

Surface coating the sample

Prior to analysis, the samples were attached to steel microscope stubs and coated with gold in an Edwards 'Scancoat six' plasma-coating unit, coating for 90 s to produce a film of approximately 100 nm thickness. Flat aluminium plates were then attached to the tops of the samples to maintain a flat surface and to facilitate a uniform electric field for accelerating secondary ions into the mass spectrometer. Secondary electron images were first obtained to give topographical details, and the gold was then sputtered away using the gallium ion beam, monitoring on a secondary ion of interest and sputtering until the signal stabilised, indicating complete removal of the gold.

SIMS equipment

The SIMS instrument was constructed at the University of Bristol comprising a focused gallium ion gun (FEI electronically variable aperture type) fitted to a Vacuum Generators model 7035 doublefocusing magnetic sector mass analyser. A Thornley-Everhard electron detector allows the acquisition of secondary electron images from the sample at spatial resolutions determined by the diameter of the ion beam. The sample potential is 4 kV and secondary ions are accelerated into the mass spectrometer through an ion extraction lens system. They then travel through an electrostatic energy filter with adjustable pass energy, a magnetic mass filter, and a slit and into a channeltron detector. A diagram of the instrument is presented in Heard et al. (2001). The spectrometer has a high transmission efficiency of secondary ions from the sample to the channeltron, with the option of high mass resolution (at a cost of lower transmission), allowing a spectral resolution, $M/\Delta M$ ratio of several thousand. For routine analyse where mass interference for the elements of interest is minimal, low spectral resolution with high transmission was selected, with resulting sensitivities in the parts per million range, depending on the element to be analysed.

The PC control software was written in house to allow control of spectral acquisition, beam scanning, image acquisition, and depth profiling, operating under the Windows system to allow easy transfer of data and images to standard spreadsheet and image manipulation packages (Dayta System Ltd, Thornbury, UK). False colour display images were created using UTHSCSA image tool version 2.03 software.

Spectrum and image acquisition

Typically mass spectra are obtained on the system by scanning through the mass range 0-100 Daltons in 0.05 Dalton steps, spending 100 ms per step and taking 200 s in all. While obtaining spectra, the ion beam is scanned over the area of interest, usually at low magnification to limit the damage caused to the specimen by sputtering.

Secondary ion images are obtained by selecting the mass/charge ratio of the ion of interest and raster scanning of the ion beam over the sample. The images presented in this paper contain 640×480 pixels and were acquired in 90 s each. For atomic species present at low concentrations, the acquisition time could be increased in order to obtain low noise images.

Analysis of S and N concentrations, and ³⁴S and ¹⁵N abundance

The abundance of ³⁴S in wheat grain was determined using a continuous flow isotope ratio mass spectrometer^{7,10}. The instrumentation used was an ANCA-SL sample converter and a 20-20 IRMS (Europa Scientific Ltd, Crewe, UK). Total S concentration was determined using inductively coupled plasma atomic emission spectrometry, after the samples were digestion with HNO₃/HClO₄ (85/ 15 v/v). Total N concentration and ¹⁵N abundance in the grain samples were quantified using a mass spectrometer (Integra, Europa Scientific Ltd, Crewe, UK).

RESULTS AND DISCUSSION

Two lines of wheat were grown with enriched ${}^{34}SO_4$ to increase the abundance of ${}^{34}S$ in the grain. These were L88-6, which forms part of a near isogenic series developed from Olympic × Gabo¹¹ and B73-6-1, which is a transgenic derivative of L88-6 in which the addition of multiple copies of the *Glu-1D* gene encoding HMW glutenin subunit 1Dx5 leads to an increase of about four fold in the amount of this protein¹².

The results obtained with the two lines were qualitatively the same and only data for B73-6-1 are presented. The samples of B73-6-1 studied contained $0.085 \pm 0.001\%$ total sulphur with a ³⁴S isotopic enrichment of 12.1 ± 0.04 atom %. The grain contained $1.72 \pm 0.05\%$ total nitrogen, and was also enriched with ¹⁵N to 12.2 ± 0.2 atom % but, this isotope was not followed in the present study.

Figure 1 shows the images obtained of a section from the central part of the starchy endosperm of a mature grain of B73-6-1 at two magnifications. The ion induced secondary electron images of the tissues clearly show the presence of cell walls and starch granules embedded in a matrix, with some fissures arising from shrinkage during sample preparation. Superimposition of the locations of C₂ and ¹⁶O show clear labelling of the starch granules while the superimposition of CN⁻ on the matrix between the starch granules is consistent with its proteinaceous nature.

Analysis of the distributions of ³²S and ³⁴S gave less sharp images but both isotopes were clearly concentrated at the starch granule surface and the interface between the granules and the matrix



Figure 1 SIMS images of the starchy endosperm cells of B73-6-1 wheat seed at low and high magnifications, showing the distribution of ions as bright areas, showing from top to bottom a secondary electron microscopy image of the samples, the location of the starch granules and protein matrix (C_2 and CN SIMS analysis respectively) and the distribution of ^{32}S , ^{34}S and ^{16}O ions by SIMS analysis.

proteins. This is seen more clearly in the high magnification images shown in Figure 2.

The SIMS images have been normalised in brightness for presentation purposes, and there is no implication that the elements are present in equal quantities. Within each image however, the brightness of each pixel is proportional to the amount of signal received at that point. Analysis of the signal strengths of isotopes ³²S, ³⁴S and ¹⁶O in different parts of the endosperm cells (see Fig. 3 and Table I) showed a higher concentration of ³⁴S at the outer surfaces of the starch granules compared to the cut interior faces of these structures. The protein matrix also had a lower concentration of ³⁴S isotope than the starch granules.

The ³²S isotope signals are stronger than the ³⁴S signals in all structures in the B73-6-1 seeds (see Table I) which was expected as ³²S accounts for 87.9% of the sulphur atoms in the samples. However, a difference was seen between the distributions of ³⁴S and ³²S isotopes in the interior of the starch granules with the ³⁴S signal being proportionally lower than that of ³²S. We consider that this could be due to corruption of the ³²S signal with that from charged particles of ¹⁶O₂, which would be expected to be formed from the ¹⁶O ions released from the carbohydrate molecules present in the starch granules after bombardment with the primary ion beam. As the signal level of ¹⁶O is two orders of magnitude higher than that of ³²S (see Table I) even a small proportion of ¹⁶O ions forming ¹⁶O₂ molecules would have a marked effect on the ³²S signal, as shown by the similarity in the ¹⁶O and ³²S images in Figure 2. The signal for ¹⁶O was highest in the centre of the granules where the ³⁴S signal was weakest; a combination of the ³²S and ¹⁶O₂ signals would therefore give a strong signal throughout the whole starch granule, as seen with the ³²S images.

The distributions of these signals are shown more clearly in Figure 4 where the use of colour display software portrays the interior of the starch granules as green/blue due to a combination of the 32 S (shown in green) and 16 O (shown in blue) signals whereas the 34 S signal (shown in red) is located predominantly at the surface of the starch granules.

This highlights the importance of using ³⁴S to obtain accurate localisation of sulphur at a subcellular resolution using the SIMS equipment.

The high concentration of sulphur at the starch granule surface may result from the presence of a high concentration of sulphur-rich proteins



Figure 2 SIMS analysis of a single starch granule from B73-6-1 wheat seed, showing secondary electron microscopy image, starch granule (C₃), protein matrix (CN¹⁴ and CN¹⁵), distribution of ³²S, ³⁴S and ¹⁶O ions and colour display image showing the positions of ³²S (blue), ³⁴S (red) and CN¹⁴ (green) ions.



Figure 3 Areas of the endosperm cells analysed for signal strength shown in both ³⁴S and CN¹⁴ images.

B73-6-1	Mean signal levels			Ratios of the mean signal levels	
	Outer section of the starch granule	Protein matrix	Whole inner section of the starch granule	Outer section/inner section of the starch granules	Outer section of the starch granule/ protein matrix
34-Sulphur 32-Sulphur 16-Oxygen	$10.66 \times 10^{-7} \\ 131 \times 10^{-7} \\ 2.55 \times 10^{-5}$	$\begin{array}{c} 2 \cdot 83 \times 10^{-7} \\ 74 \times 10^{-7} \\ 1 \cdot 45 \times 10^{-5} \end{array}$	$3 \cdot 33 \times 10^{-7}$ 90×10^{-7} $3 \cdot 55 \times 10^{-5}$	3·20:1 1·45:1 0·72:1	3·70:1 1·77:1 1·76:1

Table I Relative signal strengths for different isotopes at different structures in the endosperm cells



Figure 4 Colour display images of the oxygen (blue) interference on the ³²S signal (green) with ³⁴S shown in red.

including puroindolines, grain softness proteins (both of which are components of friabilin) and inhibitors of α -amylase^{13–18}. In particular, the puroindolines contain a total of 10–11 mol % of sulphurcontaining amino acids (cysteine and methionine)¹⁹ compared with a maximum of 5 mol % in the most sulphur-rich gluten proteins (α -gliadins, γ -gliadins and LMW subunits of glutenin)²⁰.

Advantages of SIMS technology

The study reported here illustrates the advantages and drawbacks of the SIMS technology.

Firstly, it is capable of detecting all elements, which contrasts with X-ray photoelectron spectroscopy (XPS) and energy–dispersive X-ray analysis (EDX) which have limitations with respect to hydrogen, helium and, with EDX, also lithium and beryllium. It is also unique in being able to detect all isotopes, but varies in sensitivity. For example, concentrations of electropositive elements such as sodium, potassium and lithium in the ppm to ppb range can be detected, allowing us to identify of sodium in phytin granules of wheat for the first time⁵. However, the sensitivity for less easily ionisable elements may be in the 10–100 ppm range. Of the other currently available methods only electron energy-loss spectroscopy (EELS) combined with TEM has comparable sensitivity, with EDX/WDX (wavelength dispersive X-ray spectroscopy) and XPS having sensitivities in the 0.01-0.1 wt % range.

However, SIMS is only able to resolve ions with significant differences in their mass/charge ratios. Sulphur presents a difficult challenge in this respect, with the major isotope ³²S only being resolved from

 ${}^{16}\text{O}_2$ with reduced sensitivity and the minor isotope ${}^{34}\text{S}$ being insufficiently abundant (only $4\cdot3\%$ of total sulphur) to give reliable results. We have overcome this problem by enriching grains with ${}^{34}\text{S}$ and comparing the distribution of ${}^{34}\text{S}$, ${}^{32}\text{S}$ and ${}^{16}\text{O}_2$.

In terms of spatial resolution SIMS (<100 nm) compares well with EDX/WDX with SEM (1–2 μ m) and XPS (10 μ m) but is gives lower resolution than EDX/WDX with TEM/STEM and EELS/TEM (both <10 nm). In addition quantitative analysis is more difficult than with other systems due to a number of factors including the enhancement of signals by oxygen or oxides. Nevertheless, quantitative analysis can be achieved by comparisons with control samples of similar but known composition.

Finally, SIMS does not require the preparation of sections but only a flat surface, which is similar to EDX/WDX with SEM and XPS. In contrast, EDX/WDX with TEM/STEM and EELS/TEM both require material to be cut into 50–100 nm sections.

We consider, therefore, that the range, sensitivity, spatial resolution and ease of sample preparation and handling make SIMS an attractive addition to more widely used system for the surface analysis of cereals and other biological materials.

We have not attempted to use SIMS to determine the distribution of sulphur in other plant tissues but foresee no technical problems provided freeze substitution is used to preserve inorganic sulphate.

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REFERENCES

- Wada, T. and Lott, J.N.A. Light and electron microsopic and energy dispersive X-ray microanalysis studies of globoids in protein bodies of embryo tissues and the aleurone layer of rice (*Oryza sativa L.*) grains. *Canadian Journal of Botany* **75** (1996) 1137–1147.
- Arys, A., Philippart, C., Dourov, N., He, Y., Le, Q.T. and Pireaux, J.J. Analysis of titanium dental implants after failure of osseointegration: Combine histological, electron microscopy, and X-ray photoelectron spectroscopy approach. *Journal of Biomedical, Materials, Research* 43:3 (1998) 300–312.
- Door, R., Richter, K. and Martin, R. Detection of low phosphorus contents in neurofilms of squid axons by image-EELS contrast spectroscopy. *Journal of Microscopy – Oxford* 188:2 (1997) 173–181.

- Benninghoven, A., Rudenauer F.G. and Werner H.W. 'Secondary Ion Mass Spectrometry', John Wiley & Sons, NY (1987).
- Heard, P.J., Feeney, K.A., Allen, G.C. and Shewry P.R. Determination of the elemental composition of mature wheat grain using a Modified Secondary Ion Mass Spectrometer (SIMS). *Plant Journal* **30** (2001) 237–245.
- Thode, H.G. Sulphur isotopes in nature and the environment: An overview. In 'Stable Isotopes: Natural and Anthropogenic Sulphur in the Environment', *SCOPE* 43 (H.R. Krouse and V.A. Grinenko, eds), John Wiley & Sons, Chichester, England (1991) pp 1–26.
- Zhao, F.J, Verkampen, K.C.J., Birdsey, M., Blake-Kalff, M.M.A. and McGrath, S.P. Use of the enriched stable isotope ³⁴S to study sulphur uptake and distribution in wheat. *Journal of Plant Nutrition* 24 (2001) 1551–1560.
- Zhao, F.J., Hawkesford, M.J. and McGrath, S.P. Sulphur assimilation and effects on yield and quality of wheat. *Journal of Cereal Science* **30** (1999) 1–17.
- 9. Chaffey, N.J., Barlow, P.W. and Barnett, J.R. A seasonal cycle of cell wall structure is accompanied by a cyclical rearrangement of cortical microtubules in fusiform cambial cells within taproots of Aesculus hippocastanum (*Hippocastanaceae*). New Phytologist **139:4** (1998) 623–635.
- Monaghan, J.M., Scrimgeour, C.M., Stein, W.M., Zhao, F.J. and Evans, E.J. Sulphur accumulation and redistribution in wheat (*Triticum aestivum*): a study using stable sulphur isotope ratios as a tracer system. *Plant, Cell* and Environment 22 (1999) 831–840.
- Lawrence, G.J., MacRitchie, F. and Wrigley, C.W. Dough and baking quality of wheat lines deficient in glutenin subunits controlled by the *Glu-A1*, *Glu-B1* and *Glu-D1* loci. *Journal of Cereal Science* 7 (1988) 109–112.
- Rooke, L., Bekes, F., Fido, R.J., Barro, F., Gras, P., Tatham, A.S., Barcelo, P., Lazzeri, P. and Shewry, P.R. Overexpression of a gluten protein in transgenic wheat results in greatly increased dough strength. *Journal of Cereal Science* 30:2 (1999) 115–120.
- Greenwell, P. and Schofield, J.D. A starch granule protein associated with endosperm softness in wheat. *Cereal Chemistry*, 63 (1986) 379–380.
- Blochet, J.E., Chevalier, C., Forest, E., Pebay-Peyroula, E., Gautier, M.F., Joudrier, P., Pezolet, M. and Didier, M. Complete aminoacid sequence of puroindoline, a new basic and cystine-rich protein with a unique tryptophanrich domain, isolated by Triton X-114 phase partioning. *FEBS Letters* 329 (1993) 336–340.
- 15. Jolly, C.J., Rahman, S., Kortt, A.A. and Higgins, T.J.V. Characterisation of the wheat M_r 15000 'grain softness protein' and analysis of the relationship between its accumulation in the whole seed and grain softness. *Theoretical and Applied Genetics* **86** (1993) 589–597.
- Rahman, S., Jolly, C.J., Skerritt, J.H. and Wallosheck, A. Cloning of a wheat 15 kDa grain softness protein (GSP). *European Journal of Biochemistry* 223 (1994) 917–925.
- Morris, C.F., Greenblatt, G.A., Bettge, A.D. and Malkawi, H.I. Isolation and characterisation of multiple forms of friabilin. *Journal of Cereal Science* **21** (1994) 167–174.
- Darlington, H.F., Rouster, J., Hoffman, L., Halford, N.G., Shewry, P.R. and Simpson, D.J. Identification and molecular characterisation of hordoindolines from barley grain. *Plant Molecular Biology* 47 (2001) 785–794.

- Gautier, M.F., Aleman, M.E., Guirao, A., Marion, D. and Joudier, P. *Triticum aestivum* puroindolines, two basic cystine-rich seed proteins: cDNA analysis and developmental gene expression. *Plant Molecular Biology* 25 (1994) 43–57.
- Shewry, P.R., Tatham, A.S. and Halford, N.G. 'Seed Proteins', (Shewry, P.R. and Casey, R., eds), Kluwer Academic Publishers, Netherlands (1999) pp 35–78.